

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	750				
R _{DS(on)} (Ω)	V _{GS} = 10 V 6.5				
Q _g (Max.) (nC)	38				
Q _{gs} (nC)	5.0				
Q _{gd} (nC)	21				
Configuration	Single				

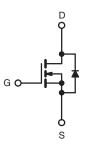
FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T_C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	750		
Gate-Source Voltage			V _{GS}	± 20	V	
Continuo Dunio Comment	\(\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	T _C = 25 °C	- I _D	1.8		
Continuous Drain Current	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$		1.2	А	
Pulsed Drain Current ^a			I _{DM}	7.2		
Linear Derating Factor				0.43	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	180	mJ	
Repetitive Avalanche Current ^a			I _{AR}	1.8	Α	
Repetitive Avalanche Energy ^a	E _{AR}	5.4	mJ			
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P _D	54	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150		
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d	°C	
Mounting Toyous	6 20 0 1	0.00140		10	lbf ⋅ in	
Mounting Torque	6-32 or M3 screw			1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 104 mH, R_g = 25 Ω , I_{AS} = 1.8 A (see fig. 12). c. I_{SD} ≤ 1.8 A, dI/dt ≤ 80 A/µs, V_{DD} ≤ 600, T_J ≤ 150 °C.

- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	UNIT					
Maximum Junction-to-Ambient	R_{thJA}	-	62			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R_{thJC}	-	2.3			

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static		1			·		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$	V, I _D = 250 μA	750	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	o 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	_{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	_S = ± 20 V	-	-	± 100	nA
Zero Osto Wellere Burio Osmod		$V_{DS} = 80$	V _{DS} = 800 V, V _{GS} = 0 V		-	100	<u> </u>
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 V, V	_{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.1 A ^b	-	6.5	-	Ω
Forward Transconductance	9fs	V _{DS} = 10	00 V, I _D = 1.1 A ^b	0.80	-	-	S
Dynamic		1		l			
Input Capacitance	C _{iss}		_{GS} = 0 V,	-	530	-	pF
Output Capacitance	C _{oss}		$_{OS} = 0 \text{ V},$ $_{OS} = 25 \text{ V},$	-	150	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 l	MHz, see fig. 5	-	90	-	
Total Gate Charge	Qg			-	-	38	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 1.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	5.0	
Gate-Drain Charge	Q _{gd}		see lig. 6 and 13		-	21	1
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V}, I_D = 1.8 \text{ A},$ $R_g = 18 \ \Omega, R_D = 230 \ \Omega, \text{ see fig. } 10^b$		-	8.2	-	- ns
Rise Time	t _r			-	17	-	
Turn-Off Delay Time	t _{d(off)}			-	58	-	
Fall Time	t _f			-	27	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.8	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	7.2	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 1.8 A, V _{GS} = 0 V ^b		-	-	1.4	V
Body Diode Reverse Recovery Time	t _{rr}		•	-	380	570	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 1.8 \text{A}, dI/dt = 100 \text{A}/\mu\text{s}^b$		-	0.94	1.4	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-	rn-on is dominated by L _S and L _D)			L _D)	

Notes

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- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

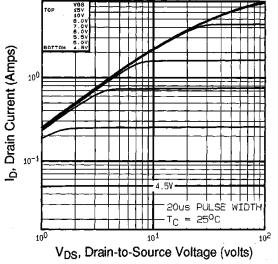


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

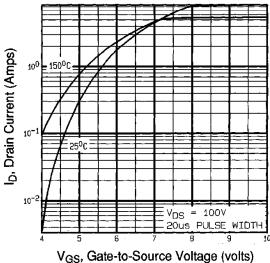


Fig. 3 - Typical Transfer Characteristics

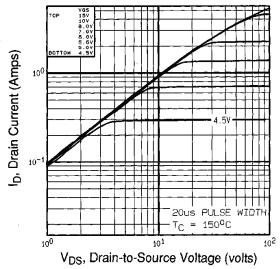


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

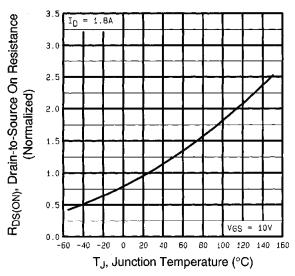


Fig. 4 - Normalized On-Resistance vs. Temperature



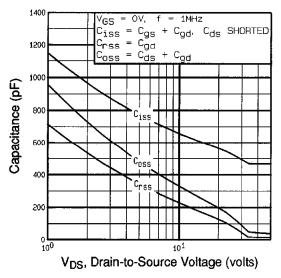


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

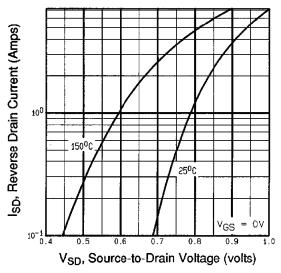


Fig. 7 - Typical Source-Drain Diode Forward Voltage

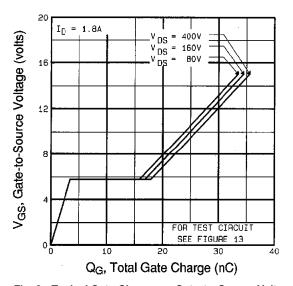


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

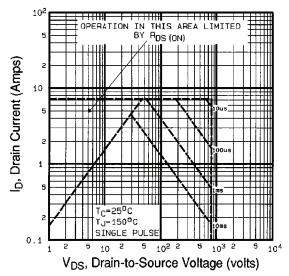


Fig. 8 - Maximum Safe Operating Area



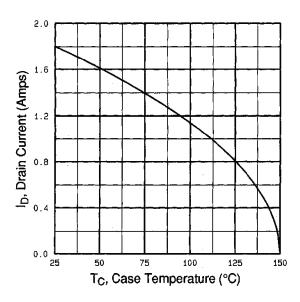


Fig. 9 - Maximum Drain Current vs. Case Temperature

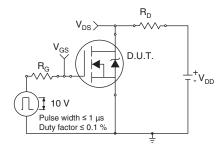


Fig. 10a - Switching Time Test Circuit

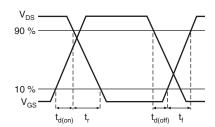


Fig. 10b - Switching Time Waveforms

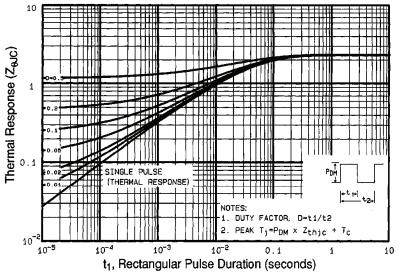
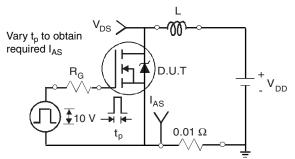
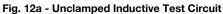


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case







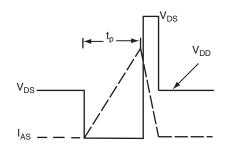


Fig. 12b - Unclamped Inductive Waveforms

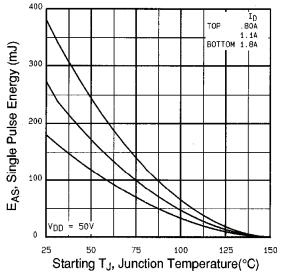


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

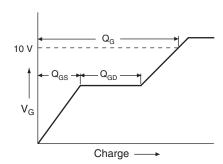


Fig. 13a - Basic Gate Charge Waveform

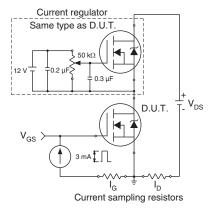
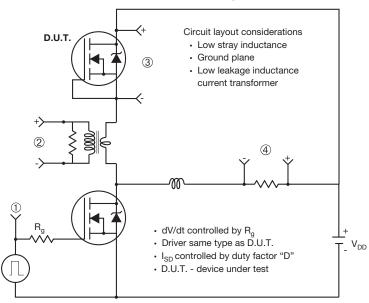


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



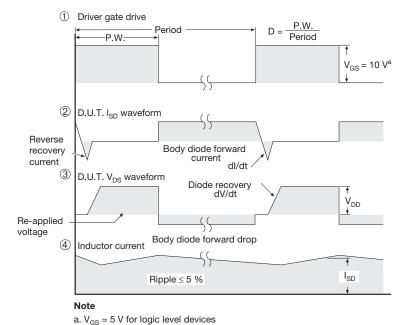
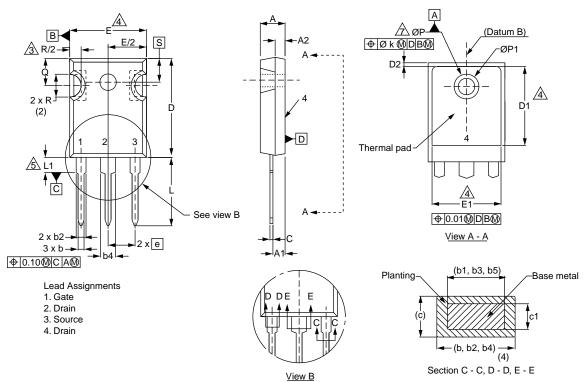


Fig. 14 - For N-Channel



TO-247AC (High Voltage)



	MILLIMETERS			HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.58	5.31	0.180	0.209	
A1	2.21	2.59	0.087	0.102	
A2	1.17	2.49	0.046	0.098	
b	0.99	1.40	0.039	0.055	
b1	0.99	1.35	0.039	0.053	
b2	1.53	2.39	0.060	0.094	
b3	1.65	2.37	0.065	0.093	
b4	2.42	3.43	0.095	0.135	
b5	2.59	3.38	0.102	0.133	
С	0.38	0.86	0.015	0.034	
c1	0.38	0.76	0.015	0.030	
D	19.71	20.82	0.776	0.820	
D1	13.08	-	0.515	-	

	MILLIM	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D2	0.51	1.30	0.020	0.051
E	15.29	15.87	0.602	0.625
E1	13.72	-	0.540	-
е	5.46	BSC	0.215	BSC
Øk	0.254		0.010	
L	14.20	16.25	0.559	0.640
L1	3.71	4.29	0.146	0.169
N	7.62	7.62 BSC		BSC
ØΡ	3.51	3.66	0.138	0.144
Ø P1	-	7.39	-	0.291
Q	5.31	5.69	0.209	0.224
R	4.52	5.49	0.178	0.216
S	5.51 BSC		0.217	' BSC



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